Stochastic Model in the Kardar-Parisi-Zhang Universality With Minimal Finite Size E ects

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We introduce a solid on solid lattice model for growth with conditional evaporation. A measure of nite size e ects is obtained by observing the time invariance of distribution of local height uctuations. The model parameters are chosen so that the change in the distribution in time is minimum. On a one dimensional substrate the results obtained from the model for the roughness exponent from three dierent methods are same as predicted for the Kardar-Parisi-Zhang (KPZ) equation. One of the unique feature of the model is that the as obtained from the structure factor S (k;t) for the one dimensional substrate growth exactly matches with the predicted value of 0.5 within statistical errors. The model can be dened in any dimensions. We have obtained results for this model on a 2 and 3 dimensional substrates. pacs60, 68.55-a,82.20 Fd

The KPZ equation [l] is one of the most studied stochastic equation in the eld of growth.

$$\frac{\partial h}{\partial r} = {}_{0}r^{2}h + (r h)^{2} +$$
 (1)

Here, h(r;t) is the height function, is coupling parameter, and (r;t) is (r;t) $(r^0;t^0) > =$ (r r^0 ; t t^0). Gaussian noise with the correlation < First term is a linear term [2] referred as Edward-Wilkinson (EW) term. Applications and uses of KPZ equation have been well demonstrated [3]. In particular its use in understanding growth phenomenon has lead to vigorous activities in development of theoretical methods [4,5], lattice models [6,7,8] and numerical methods [9] built around Eq. (1). The critical exponents in (1+1) dimensions are exactly obtainable [10]. However, in all the higher dim ensions the determ ination of these exponents has been a di cult task. It is well known that this equation shows phase transition in dimensions higher than its critical dimension (2+1) [10] as a function of its coupling parameter. For weak coupling case the coupling constant renormalizes to zero leading to a linear equation. For strong coupling case, the perturbation approach fails and other methods are required. However, obtaining exact values for the exponents has never been possible although the ranges in which exact values are expected to fall are evident from the available references [4, 5, 6, 7, 8, 9].

Various lattice models have been devised [6, 7, 8] that are known to belong to the KPZ universality in the asymptotic region. Most of the models su er from nite size e ects arising from cuto length a and the substrate size L.O ne of the tests to probe the presence of nite size e ects is to determ ine the growth exponents by dierent methods such as height-height (h-h) correlations, structure factor $S(k;t) = \langle h(k;t)h(k;t) \rangle$, from saturated widths W sat, etc.. For any given lattice model, the values obtainable from these m ethods can be statistically di erent. Since all these m odels are expected to converge asymptotically to KPZ behavior, the apparent mism atch of the exponent values from dierent methods will be due to the nite size e ects. On the other hand if a model gives same exponents within statistical errors, it is expected to be free of nite size e ects. In the following we propose a model that we believe to belong to the KPZ universality and, in (1+1) dimensions, it provides the values of the exponent same within the statistical error, using three di erent methods of determination. This value also compares well with the exactly known value in (1+1) dimensions, 0.5.

We describe them odelbelow and the changes therein for (2+1) and (3+1)

dim ensions. A site is chosen random ly and height at the site is increased by unity signaling random deposition on the substrate. The deposited atom is conditionally accommodated, otherwise evaporated. In (1+1) dimensions the deposited atom is accommodated if both its neighbors have at least same height as the deposited one. O therwise, largest of the height di erences at the site i and the nearest neighboring sites, $s_d = m$ ax $(h_i h_j)$; j = i + 1; i 1, is obtained and accomm odation is allowed according to the probability factor $e^{-s_d^2=(2^{-2})}$. Thus s_d is the largest local step. Choice of depends upon the behavior of the model for the given value of . We choose the value of that leads to m in im um variation in the local height uctuations. M odel with is expected to be least a ected by the nite size e ects [11]. It has been shown in reference [11] that a measure of nite size e ects for a given lattice model can be obtained from the distribution of local height uctuations. In this method, we de ne the local height $(h_i(t))_{local} = h_i(t)$ $(h_{i-1}(t) + h_{i+1}(t))=2$ with respect to the local reference as the average of nearest neighbor heights. Sim ilarly we measure (h_i (t+ t)) $_{local}$ where t> w (t). w (t) is the width of the interface at t, and the inequality ensures that the di erence between localheights measured attandt+ tare uncorrelated. Thus we measure the distribution of uncorrelated uctuations h (t) local from the dierence $h(t)_{local} = (h_i(t))_{local}$ $(h_i(t+t))_{local}$. Fig. 1 shows such a distribution for = 1:7. A nother distribution is obtained at later time and compared with the earlier one. In our case we have obtained distributions att=500 M Ls and t=5000 M Ls for comparison with t= 100 M Ls. Since the counts at h(t) $_{local}$ = 0 are largest in the distribution, the statistical error is m in im um for zero uctuation. We therefore use the parameter P_0 = $100 \left(\frac{I_{500} \quad I_{500}}{I_{500}}\right)$, where I_t is the count at h(t) local = 0 to measure the time invariance of the distribution of h(t) local in (1+1) and (2+1) dimensions. In (3+1) dimensions, t and times for comparison are smaller due to the large computation times involved. Ideally P_0 should be zero. In the present context we look for a minimum value of P_0 as a function of . The ratios P_0 are obtained by averaging over large enough runs so that values of P_0 are statistically discriminated for dierent values of . It has been shown in reference [11] that this method is useful in identifying presence of nite size e ects for any lattice model belonging to KPZ or EW universality. Fig. 2 shows the variation of P_0 with for the model described. We have measured P_0 for the model with dierent values on a substrate of length L = 40000. As can be seen, the m in im um occurs at = 1.7. We have therefore used this

value in (1+1) dimensions. For other values of we found that value of as obtained from structure factor deviates from 0.5 and the linear range is also reduced on the log-log plot. This con rm s the electiveness of the method for determining nite size elects [11].

In (2+1) dimensions the deposited atom is accommodated if three ormore nearest neighbors have at least same height as its own. If this condition is relaxed to less number of in-plane neighbors, cross over due to EW region is obtained. The cross over is negligible when direct accommodation with three or four in-plane neighbors is allowed. For depositions at the site with less than three in-plane neighbors, the accommodation is decided from the largest of the four steps around the site using the exponential probability factor $e^{s_d^2=(2^{-2})}$. In (2+1) dimensions we have observed that $e^{s_d^2=(2^{-2})}$. In $e^{s_d^2=(2^{-2})}$. The substrate size is $e^{s_d^2=(2^{-2})}$.

In (3+1) dim ensions the deposited atom is accommodated if 5 or 6 nearest neighbors have at least same height as the deposited atom. We have used = 4.5 in the simulations since this value gives minimum $P_0=0.0012-0.001\%$. The t=20M Ls and the distributions are compared for the times 50 M Ls and 500 M Ls for the substrate size of L=100.

W e present results obtained from (h-h) correlations, W $_{\rm sat}$ as a function of L , and structure factor. The (h-h) correlation is

G (x;t) =
$$\frac{1}{N} \frac{X}{x^0}$$
 (h (x + x⁰;t) h (x⁰;t))²
= x^2 f $\frac{X}{(t)}$ (2)

where, correlation length (t) t^{1-z} . In the lim it x ! 0, f ! 1. the width over a substrate of length L as,

$$w_{2}(L;t) = \frac{1}{N} {x \choose x} (h(x;t) h(t))^{2}$$

= $L^{2} g \frac{L}{(t)}$; (3)

Here h (t) is the average height at time t. It can be shown that [10] for times t>> L,g $\frac{L}{(t)}$! const:, thus w_{sat} / L^2 . For t<< L w_2 (t) / t^2 .

The structure factor S (k;t) is measured as

$$S(k;t) = \langle h(k;t)h(k;t) \rangle$$
 (4)

where $h(k;t) = (1=N)^{P}_{x}(h(x;t) h(x;t))e^{ikx}$.

Figures (3), (4) and (5) sum marize the results obtained for the model in (1+1) dimensions. Fig. 3 shows the log-log plot of G (x;t) Vs. x. The straight line is tted between x=8 and 500. The slope gives =0.504 0.002. Fig. 4 shows plot of W $_{\rm sat}$ Vs. L for (1+1) dimensions. The least square to the points gives =0.502 0.005.

Fig. 5 shows log-log plot of < h (k;t)h (k;t) > Vs. k. The straight line t is between k=0.03 to 1.25. The slope near k=1 tends to zero [12]. The slope is 2.003-0.021. This gives [10] =0.500-0.021. Earlier, in reference [13] for the etching model, a slope 1.92-0.02 was obtained in the range of k=0.05 to 0.1, resulting in =0.46. This was considered to be one of the best value obtained for the existing lattice models by this method. Clearly the present model provides a better value. In the same reference, =0.496 is obtained from the W $_{\rm sat}$. The apparent dierence in the two values indicates the presence of nite size e ect for the etching model. In the present model, the slope is una ected at smaller k values. We have tested it up to k=0.005.

Above results show that the proposed model has minimal nite size effects. It further con ims the method introduced in reference [11] for determination of nite size elects in a lattice model. We have applied this method in (2+1) dimensions and in (3+1) dimensions to choose the model parameters corresponding to the minimal nite size elects.

In Fig. 6, we display the results of W $_{\rm sat}$ Vs. L in (2+1) dimensions. The led squares are the values calculated from the simulation results. The corresponding t gives = 0:357 0:005. Fig. 7 shows the log-log plot of G (x;t) Vs. x. From its slope, = 0:355 0:001. The line is tted between x = 2 to 50. Thus both the methods give results matching within statistical margin.

In Fig. 6, we have also plotted the results of W $_{\rm sat}$ V s. L for the m odel in (3+1) dimensions. It gives = 0.289 0.005. The values obtained from these m odels in (2+1) and (3+1) dimensions are very close to those predicted in reference [14]. In this reference = 0.35702 for (2+1) dimensions and 0.28125 for (3+1) dimensions.

We have also measured the values for these models from the log-log plots of w_2 (t) Vs. t. We obtain = 0.332 0.001 ,0.221 0.002 and

0:168 0:003 for (1+1), (2+1) and (3+1) dimensions respectively. These values are consistent with the universal relation +z=2 for the KPZ equation [10].

In conclusion, we have developed a lattice model belonging to the KPZ universality with minimum nite size e ects. That the nite size e ects are minimum is evident from the results obtained. The value using W $_{\rm sat}$ V s. L , G (x;t) V s. x , and from S (k;t) V s. k plots are equal within statistical margin in (1+1) dimensions. The simulation values are very close to the exact , 0.5. M easurement involving local height uctuations is successfully used in determining the nite size e ects in lattice models. The models with minimum nite size e ects are expected to lead to the better accuracy in determining the exact exponents for KPZ growth in higher dimensions. In (2+1) dimensions, we have obtained values close to = 0:36 while in (3+1) dimensions it is around 0.29. Both these values are close to the earlier prediction in reference [14].

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Figure 1: Plot of distribution of h (t) $_{local}$ for the (1+1) dimensional model discribed in the text on semilog scale. The distribution is for t = 5000 M Ls, with = 1:7. The distribution is obtained by collecting the data over 3000 runs.

Figure 2: Plot of P_0 in % as a function of parameter for the model in (1+1) dim ensions.

Figure 3: Plot of G (x;t) V s. x on log-log scale. The substrate size L= 80000, and the number of m onolayers grown are 5×10^5 .

Figure 4: Plot of W $_{\rm sat}$ V s. L on log-log scale for the model in (1+1) dim ensions.

Figure 5: Plot of S (k;t) Vs. k on log-log scale for the model in (1+1) dim ensions. The points are averaged over the substrate lengths of L=800, 900,1000,1200,1300,1350. k varies from =100 to .

Figure 6: Plot of W $_{\rm sat}$ V s. L on log-log scale for the model in (2+1) dim ensions (lled squares) and for the model in (3+1) dim ensions (lled circles).

Figure 7: Plot of G (x;t) Vs. x on $\log-\log$ scale for the model in (2+1) dimensions. The substrate size is L=800, and the number of monolayers grown are 20000.













